



Recent Advances in the Technologies and Applications of Terahertz Imaging

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Deadline for manuscript
submissions:

closed (30 January 2023)

Message from the Guest Editors

Dear Colleagues,

Terahertz (THz) waves lie between the microwave and infrared bands in the electromagnetic spectrum from 30 μm to 3000 μm . Terahertz spectroscopy and imaging have the characteristics of non-ionization, non-invasiveness, high penetration, high resolution, and spectral fingerprint and have broad application prospects in the non-destructive evaluation of various materials, qualitative and quantitative research in the field of biomedicine, etc.

Despite decades of development, terahertz technology still faces challenges in practical applications. In this context, this Special Issue aims to collect and report the latest developments in terahertz imaging in basic science and practical applications. Reviews and original research articles are very welcome. We look forward to your active participation in this Special Issue.

Dr. Jean-Paul Guillet

Guest Editor





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Message from the Editor-in-Chief

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